

Table of Contents

Preface

Ion Beam Induced Amorphization of Crystalline Solids: Mechanisms and Modeling H. Trinkaus	3
Surface Effect on the Nature of Damage Production in Ion-Irradiated Solids: A Molecular Dynamics Investigation M. Ghaly and R.S. Averbach	13
The Thermal Spike Model: A Possible Way to Describe the Effects Induced in Y₂O₃ by Swift Heavy Ion Irradiations C. Dufour, S. Hemon, F. Gourbilleau, E. Paumier and E. Dooryhee	21
Stopping Power and Range Relations for Low and High Z Ions in Solids: A Critical Analysis H.S. Virk and G.S. Randhawa	33
Modeling of Ion Implantation and Diffusion in Si M.-. Caturla, T. Diaz de la Rubia and P.J. Bedrossian	41
Crystal-Grid Investigation of Atomic Collision Cascades in Ionic Compounds M. Jentschel, K.H. Heinig, H.G. Börner and C. Doll	49
Thermal Spike Description of the Damage Creation in Y₃Al₅O₁₂ Induced by Swift Heavy Ions A. Meftah, M. Djebara, N. Khalfaoui, J.P. Stoquert, F. Studer and M. Toulemonde	53
Track Formation in Metals under Swift Heavy Ion Bombardment Y.N. Yavinskii	57
Diffusion in Ion Irradiated Nickel: Determination of Atomic Mixing, Sink Strength and Fraction of Freely Migrating Defects P. Fielitz, M.P. Macht, V. Naundorf and H. Wollenberger	61
Ion-Beam Modification of Semiconductors and Related Electronic Materials R.G. Elliman	67
Ion Beam Induced Epitaxial Crystallization of Buried SiC Layers in Silicon J.K.N. Lindner, K. Volz and B. Stritzker	73
Ion Beam Induced Epitaxial Regrowth and Interfacial Amorphization of Compound Semiconductors E. Glaser, T. Fehlhaber, R. Schulz and T. Bachmann	79
Effects of Ion Irradiation on Ferromagnetic Thin Films J.E.E. Baglin, M.H. Tabacniks, R. Fontana, A.J. Kellock and T.T. Bardin	87
Special Surface Structures in Surface Alloy Growth D.J. O'Connor, J. Yao and Y.G. Shen	95
Charge Carrier Lifetime Modificaiton in Silicon by High Energy H⁺, He⁺ Ion Implantation N.Q. Khanh, P. Tüttö, E.N. Járóli, O. Buiú, L.P. Biró, F. Pászti, T. Mohácsy, C. Kovacsics, A. Manuaba and J. Gyulai	101
Range Parameters of Aluminium Implanted Targets M. Hayes, E. Friedland and T. Hauser	107
Identifitcation of Bandgap States in Semiconductors by Transmutation of Implanted Radioactive Tracers N. Achtziger	113
Hall Effect Measurements on Transmutation Doped Semiconductors G. Rohrlack, K. Freitag, C. von Nathusius, R. Vianden, R. Gwilliam and B.J. Sealy	119
Characterization of Cu/Al₂O₃ Interfaces after Heavy Ion Irradiation K. Neubeck, M. Rodewald, R. Riemenschneider, D.M. Rück, H. Baumann, H. Hahn and A.G. Balogh	125
In-Depth Characterization of Damage Produced by Swift Heavy Ion Irradiation Using a Tapping Mode Atomic Force Microscope L.P. Biró, J. Gyulai and K. Havancsák	129
Hardness Enhancement and Crosslinking Mechanisms in Polystyrene Irradiated with High Energy Ion-Beams E.H. Lee, G.R. Rao and L.K. Mansur	135

Diffusion Studies in Polymers Using MeV Ion Beams A.S. Clough, D.W. Drew, M. van der Grinten, P.M. Jenneson and T.E. Shearmur	147
Ion Induced Passivation of Metal Surfaces: The Phenomenon and its Origins J.E.E. Baglin, M.H. Tabacniks, A.J. Kellock, N.S. Somcio and T.T. Bardin	155
Flux Pinning by Columnar Defects in Bi₂Sr₂CaCu₂O₈-Thin Films F. Hillmer, G. Wirth, P. Haibach, U. Frey, T. Kluge, G. Jakob and H. Adrian	159
Depth Resolved Oxygen Analysis at the Interfaces of Au-Al Layers A. Markwitz and G. Demortier	163
Substrate Influence on Topography and Chemical Composition of Thin Metal Films Produced by Means of Self-Ion Assisted Deposition I.S. Tashlykov, V. Vishnyakov and A. Wirth	167
Radiation Damage and Amorphization Mechanisms in Xe⁺ Irradiated CuInSe₂ Single Crystals M.V. Yakushev, I.S. Tashlykov, R.D. Tomlinson, A.E. Hill and R.D. Pilkington	171
Ion Beam Mixing in Epitaxial Ag/Fe/Ag-(001)-Layers Investigated with Ferromagnetic Resonance and X-Ray-Diffraction D. Kurowski, J. Pelzl, K. Brand, P. Sonntag and P. Grünberg	177
Thermal Depth Profiling of Nickel after He-Ion Irradiation D. Kurowski, G. Kalus, K. Brand, B.K. Bein and J. Pelzl	181
The Role of Surface Carbon Contamination on the Tribological Properties of Ion-Implanted 100Cr6 Bearing Steel A. Faussemagne, A. Benyagoub, P. Kapsa, H. Jaffrezic and G. Marest	185
Ion Implantation into Stainless Steel - Depth Selective Phase Analysis with an Improved Mössbauer Technique G. Walter, B. Stahl, R. Gellert, R. Nagel, D.M. Rück, G. Klingelhöfer and E. Krankelait	189
Formation of Aluminum Gradient Films on Stainless Steel by Ion Implantation R.M. Hausner, H. Baumann, K. Bethge, F. Noli and P. Misaelides	193
Studies on Ion Beam Modification and Analysis Using the Bucharest Cyclotron B. Constantinescu, C. Sarbu, E. Ivanov, D. Plostinaru and R. Bugoi	197
Microstructure and Tribology of Carbon Implanted High-Speed-Steel F. Jährling, G. Walter, D.M. Rück and H. Fuess	201
Investigation of High Fluence Carbon Ion Implanted Titanium A. Königer, A. Wenzel, C. Hammerl and B. Rauschenbach	205
Depth Distributions and Wear Behaviour of Ion Implanted Ti6Al4V H. Schmidt, H. Baumann and D.M. Rück	209
Defect Formation in irradiated Nanostructured Materials M. Rose, A.G. Balogh and H. Hahn	213
TiN Coatings Formed by Dual Beam IBAD Technique B. Rajchel, J. Stanek, E. Wantuch, T. Burakowski, J. Fedotova and A. Sellmann	217
Creation of the DLC Layer by the Dual Beam IBAD Technique B. Rajchel, J. Stanek, E. Wantuch, T. Burakowski, J. Fedotova, M. Drwięga, E. Lipińska and A. Sellmann	221
Application of High Energy Ion Beams for Local Lifetime Control in Silicon P. Hazdra and J. Vobecký	225
Ion Implantation Induced Damage Accumulation Studied by Rutherford Backscattering Spectrometry and Spectroscopic Ellipsometry T. Lohner, N.Q. Khánh, P. Petrik, M. Fried, E. Kótai and J. Gyulai	229
Plasma Immersion Ion Implantation of Nitrogen into Porous Silicon Layers A. Manuaba, I. Pintér, E. Szilágyi, G. Battistig, C. Ortega, A. Grosman and G. Amsel	233
Formation of Buried SiC Layers in Silicon by Ion Beam Synthesis K. Volz, J.K.N. Lindner and B. Stritzker	237
Lattice Damage of Relaxed Si_{1-x}Ge_x Alloys of Various Composition Implanted with 2 MeV Si Ions J.K.N. Lindner	241
Auger Depth Profiling with Good Depth Resolution of Low Energy Implantation Induced Ion Mixing A. Sulyok, A. Galisova and M. Menyhard	245

Defect Formation by Low Energy Ions during Sputter Deposition of TiW and Au on Epitaxially Grown n-Si at Different Plasma Pressures	
P.N.K. Deenapanray, F.D. Aurret, G. Myburg, M. Hayes, W.E. Meyer and C. Schutte	249
Pulsed Electron Beam Annealing of GaAs after High Dose Implantation of Hydrogen	
T. Hauser, L. Bredell, H. Gaigher, H. Alberts, A. Botha, M. Hayes and E. Friedland	253
Dose Rate and Temperature Dependence of the Crystallization Rate during IBIEC in InAs	
R. Schulz, T. Fehlhaber, E. Glaser and F. Schrempel	257
Damage Production in Ion Implanted III-V Compounds: A Comparative Study	
E. Wendler	261
The Behaviour of ^{12}B in CdTe Studied with β-NMR Techniques	
E. Oldekop, V. Eyert, F. Niedermeyer, M. Wienecke and W.-. Zeitz	267
Ion Beam and Electrical Conductivity Analysis of Nanocrystalline α-BN and α-Al₂O₃ Ceramics Implanted with Ti⁴⁺ Ions and Annealed	
S.M. Duvanov, A.V. Kabyshev and A.P. Kobzev	271
Nucleation and Growth of the Amorphous Phase in Na-Irradiated Quartz	
F. Harbsmeier and W. Bolse	279
Vacancy Type Defects in Proton Irradiated SiC	
W. Puff, A.G. Balogh, P. Mascher and H. Baumann	285
On the Amorphization of the Si/Ge Superlattices upon Ion Bombardement	
N.A. Sobolev, K. Gartner, U. Kaiser, U. Konig, H. Presting, B. Weber, E. Wendler and W. Wesch	289
Application of HIERDA to Strontium Bismuth Tantalate Ferroelectric Films	
P. Johnston, W.B. Stannard, J.F. Scott, I.F. Bubb, M. El Bouanani, D.D. Cohen and N. Dytlewski	295
Void Formation and Surface Rippling in Ge Induced by High Energetic Au Irradiation	
H. Huber, W. Assmann, R. Grötzschel, H.D. Mieskes, A. Mücklich, H. Nolte and W. Prusseit	301
Micro-IBA and Micro-AMS for Geological Materials	
S.H. Sie, T.R. Niklaus and G.F. Suter	313
Long and Short Range Order in Ion Irradiated Ceramics Studied by IBA, EXAFS and Raman	
W. Bolse, J. Conrad, F. Harbsmeier, M. Borowski and T. Rödle	319
Progress in Non-Standard Defect Analysis by RBS	
K. Gärtner	327
Heavy Ion Recoil Time of Flight Method for Materials Analysis	
D.D. Cohen, N. Dytlewski, J. Martin and R. Siegele	333
Transition-Metal Silicide Layer Formation, the Phases of Mixed Silicides	
I. Dézsi, C. Fetzner, I.S. Szűcs, J. Dekoster and G. Langouche	339
Composition and Structure of Codeposited Layers on Plasma Facing Components in Controlled Fusion Devices: Ion Beam and Microscopy Studies	
M. Rubel and P. Wienhold	345
Ion-Beam Analysis of Solar-Cell Materials	
H. Metzner	351
Evaluation of Coatings Produced by Low-Energy Ion Assisted Deposition of Co on Silicon	
I.S. Tashlykov, G. Carter and J.S. Colligon	357
Application of the Combined Channeling Method at Higher Ion Energies on Cyclotron	
F. Ditrói, J.D. Meyer, R.W. Michelmann and K. Bethge	361
Corrosion Depth Profiles by Rutherford Backscattering Spectrometry and Synchrotron X-Ray Reflectometry	
E. Szilágyi, L. Bottyán, L. Deák, E. Gerdau, V.N. Gittsovich, A. Gróf, E. Kótai, O. Leupold, D.L. Nagy and V.G. Semenov	365
Hydrogen Elastic Recoil Detection Depth Resolution and Sensitivity as a Function of Sample Composition	
L.S. Wielunski, G.L. Harding and A. Bendavid	369
Investigation of the Morphology of Porous Silicon by Rutherford Backscattering Spectrometry	
E. Szilágyi, Z. Hajnal, F. Pászti, O. Bui, G. Craciun, C. Cobianu, C. Savaniu and É. Vázsonyi	373
Combining RBS and FTIR Spectroscopy for the Ge Analysis in Si_{1-x}Ge_x Single Crystals	
A. Gerhardt, J. Donecker, B. Selle and J. Wollweber	377
Hydrogen and Nitrogen Loss during ERD Analysis of Silicon (Oxy)nitrides	
S.G. Wallace, A.C. Kockelkoren, M.G. Boudreau, P. Mascher, J.S. Forster and J.A. Davies	381

Composition and Structural Evolution of Al-Me Alloys (Me = Fe, Cu, Sb) Prepared by Means of Ultrarapid Quenching from the Melt Studied by RBS Technique V.G. Shepelevich and I.I. Tashlykova-Bushkevich	385
Diffusion of Water into Quartz and Silica Glass O. Dersch, A. Zouine, F. Rauch and E. Arai	389
Lattice Location of Hf in Near-Stoichiometric LiNbO₃: RBS/Channeling and PAC Studies J.G. Marques, A. Kling, L. Rebouta, M.F.d. Silva, A.A. Melo, J.C. Soares, M.D. Serrano, E. Diéguez and F. Agulló-López	395
(1 - 3) MeV / amu Heavy Ion Irradiation Effects on Optical Properties of Al₂O₃ V.A. Skuratov, S.M. Abu-Al Azm and V.A. Altynov	399
Ion Beam Analysis and Applications in On-Line Monitoring of Ion Induced Modifications of Materials D.K. Avasthi	405
Thin-Film Morphology and Rutherford Backscattering Spectrometry T. Hahn, H. Metzner, M. Gossila and J. Conrad	409
Electronic Sputtering and Desorption Effects in TOF-SIMS Studies Using Slow Highly Charged Ions like Au⁶⁹⁺ T. Schenkel, M.A. Briere, H. Schmidt-Böcking, K. Bethge and D. Schneider	413
Ion Channeling Study of GaN Single Crystals A. Turos, L.J. Nowicki, A. Stonert, M. Leszczyński, I. Grzegory and S. Porowski	419
Highly Focused Ion Beams in Integrated Circuit Testing K.M. Horn, P.E. Dodd and B.L. Doyle	427
Atomic Structure and Electrical Properties of a Supertip Gas Field-Ion Source T. Miller, A. Knoblauch and S. Kalbitzer	433
High Energy Ion Microprobes: Where are we going? T. Butz and R.-. Flaggmeyer	439
Application of Highly Focused Ion Beams L. Bischoff and J. Teichert	445
Use of an Ultra-High Resolution Magnetic Spectrograph for Materials Research D.O. Boerma, W.M. Arnoldbik and W. Wolfswinkel	451
Ion Beam Analysis with Monolayer Depth Resolution H.D. Carstanjen	459
Applications of Ion Track Filters S. Amrita Kaur, H.S. Virk and S.K. Chakarvarti	467
Theoretical and Experimental Study of the Stationary and Kinetic Characteristics of the Thermo-Field Ion Sources N.V. Egorov and B.V. Yakovlev	471
Status of a New Analytical Facility Based on the 2 MeV Electrostatic Accelerator in the Institute of Applied Physics I. Karnaukhov, O. Ehichev, P. Gladikh, S. Lebed, V. Miroshnichenko, A. Mytsykov, A. Shcherbakov and V. Storizhko	477